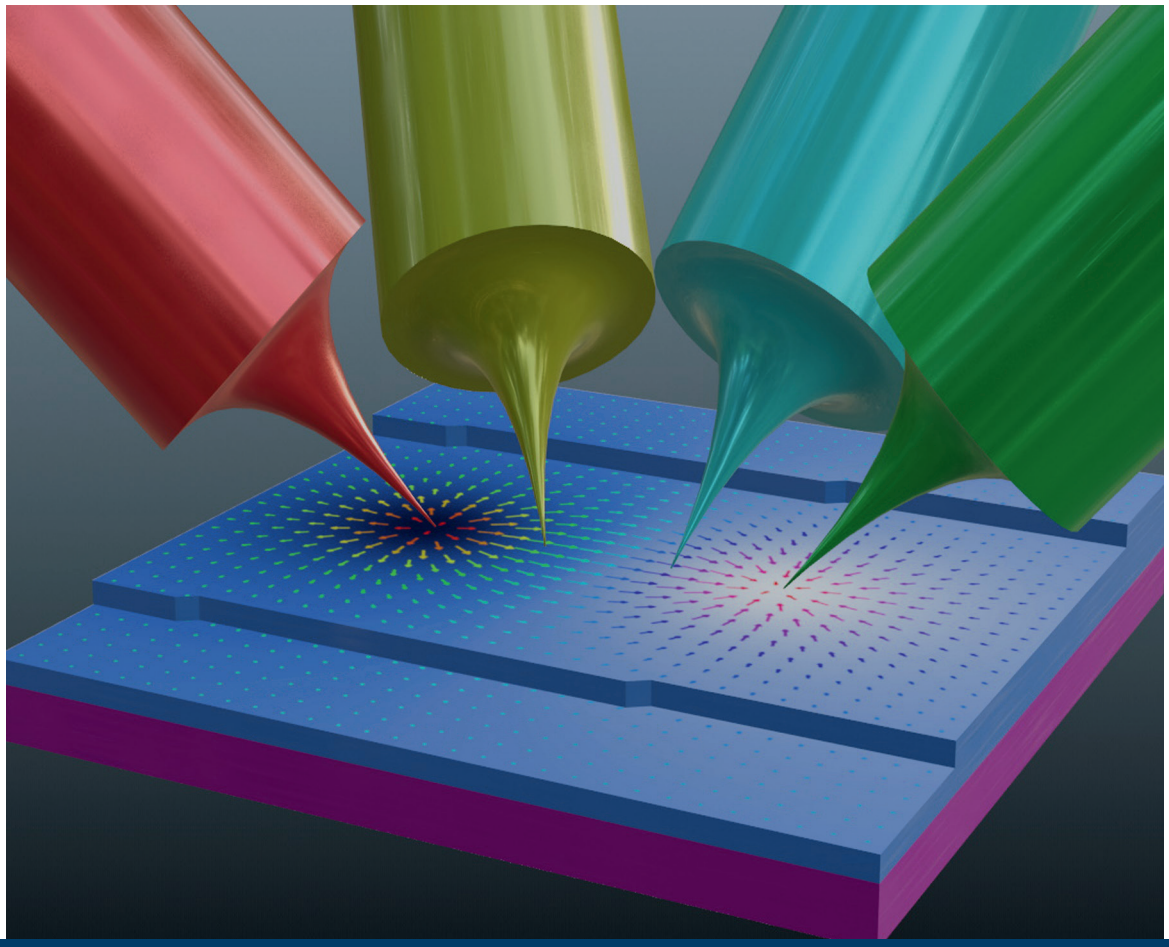

Nanoscale four-point charge transport measurements in topological insulator thin films

Arthur Leis

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